

Unclamped Collector–To–Emitter Avalanche Characteristics ($-55^{\circ} \leq T_J \leq 175^{\circ}\text{C}$)

	Symbol	Value	Unit
Single Pulse Collector–to–Emitter Avalanche Energy			
$V_{CC} = 50\text{ V}, V_{GE} = 5.0\text{ V}, P_k I_L = 16.7\text{ A}, R_G = 1000\ \Omega, L = 1.8\text{ mH}, \text{Starting } T_J = 25^{\circ}\text{C}$	E_{AS}	250	mJ
$V_{CC} = 50\text{ V}, V_{GE} = 5.0\text{ V}, P_k I_L = 14.9\text{ A}, R_G = 1000\ \Omega, L = 1.8\text{ mH}, \text{Starting } T_J = 150^{\circ}\text{C}$		200	
$V_{CC} = 50\text{ V}, V_{GE} = 5.0\text{ V}, P_k I_L = 14.1\text{ A}, R_G = 1000\ \Omega, L = 1.8\text{ mH}, \text{Starting } T_J = 175^{\circ}\text{C}$		180	
Reverse Avalanche Energy			
$V_{CC} = 100\text{ V}, V_{GE} = 20\text{ V}, P_k I_L = 25.8\text{ A}, L = 6.0\text{ mH}, \text{Starting } T_J = 25^{\circ}\text{C}$	$E_{AS(R)}$	2000	mJ

Thermal Characteristics

	Symbol	Value	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	1.2	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction to Ambient DPAK (Note 1)	$R_{\theta JA}$	95	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	T_L	275	$^{\circ}\text{C}$

1. When surface mounted to an FR4 board using the minimum recommended pad size.

Electrical Characteristics - OFF

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit
Collector–Emitter Clamp Voltage	BV_{CES}	$I_C = 2.0 \text{ mA}$	$T_J = -40^\circ\text{C}$ to 175°C	325	350	375	V
		$I_C = 10 \text{ mA}$	$T_J = -40^\circ\text{C}$ to 175°C	340	365	390	
Zero Gate Voltage Collector Current	I_{CES}	$V_{CE} = 15 \text{ V}$ $V_{GE} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$	–	0.1	1.0	μA
			$T_J = 25^\circ\text{C}$	0.5	1.5	10	
		$V_{CE} = 175 \text{ V}$ $V_{GE} = 0 \text{ V}$	$T_J = 175^\circ\text{C}$	1.0	25	100*	
Reverse Collector–Emitter Clamp Voltage	$BV_{CES(R)}$	$I_C = -75 \text{ mA}$	$T_J = 25^\circ\text{C}$	30	35	39	V
			$T_J = 175^\circ\text{C}$	35	39	45*	
			$T_J = -40^\circ\text{C}$	30	33	37	
Reverse Collector–Emitter Leakage Current	$I_{CES(R)}$	$V_{CE} = -24 \text{ V}$	$T_J = 25^\circ\text{C}$	0.05	0.25	1.0	mA
			$T_J = 175^\circ\text{C}$	1.0	12.5	25	
			$T_J = -40^\circ\text{C}$	–	0.03	0.25	
Gate–Emitter Clamp Voltage	BV_{GES}	$I_G = \pm 5.0 \text{ mA}$	$T_J = -40^\circ\text{C}$ to 175°C	12	12.5	14	V
Gate–Emitter Leakage Current	I_{GES}	$V_{GE} = \pm 5.0 \text{ V}$	$T_J = -40^\circ\text{C}$ to 175°C	200	300	350*	μA
Gate Resistor	R_G	–	$T_J = -40^\circ\text{C}$ to 175°C	–	70	–	Ω
Gate–Emitter Resistor	R_{GE}	–	$T_J = -40^\circ\text{C}$ to 150°C	14.25	16	25	k Ω

*Maximum Value of Characteristic across Temperature Range.

3. Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2\%$.

Electrical Characteristics - ON (Note 4)

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit			
Gate Threshold Voltage	$V_{GE(th)}$	$I_C = 1.0\text{ mA}$, $V_{GE} = V_{CE}$	$T_J = 25^\circ\text{C}$	1.5	1.8	2.1	V			
			$T_J = 175^\circ\text{C}$	0.7	1.0	1.3				
			$T_J = -40^\circ\text{C}$	1.7	2.0	2.3*				
Threshold Temperature Coefficient (Negative)	-	-	-	3.8	4.6	6.0	mV/°C			
Collector-to-Emitter On-Voltage	$V_{CE(on)}$	$I_C = 6.5\text{ A}$, $V_{GE} = 3.7\text{ V}$	$T_J = 25^\circ\text{C}$	0.95	1.15	1.35	V			
			$T_J = 175^\circ\text{C}$	0.7	0.95	1.15				
			$T_J = -40^\circ\text{C}$	1.0	1.3	1.40				
		$I_C = 9.0\text{ A}$, $V_{GE} = 3.9\text{ V}$	$T_J = 25^\circ\text{C}$	0.95	1.25	1.45				
			$T_J = 175^\circ\text{C}$	0.8	1.05	1.25				
			$T_J = -40^\circ\text{C}$	1.1	1.4	1.5				
		$I_C = 7.5\text{ A}$, $V_{GE} = 4.5\text{ V}$	$T_J = 25^\circ\text{C}$	0.85	1.15	1.4				
			$T_J = 175^\circ\text{C}$	0.7	0.95	1.2				
			$T_J = -40^\circ\text{C}$	1.0	1.3	1.6*				
		$I_C = 10\text{ A}$, $V_{GE} = 4.5\text{ V}$	$T_J = 25^\circ\text{C}$	1.0	1.3	1.6				
			$T_J = 175^\circ\text{C}$	0.8	1.05	1.4				
			$T_J = -40^\circ\text{C}$	1.1	1.4	1.7*				
		$I_C = 15\text{ A}$, $V_{GE} = 4.5\text{ V}$	$T_J = 25^\circ\text{C}$	1.15	1.45	1.7				
			$T_J = 175^\circ\text{C}$	1.0	1.3	1.55				
			$T_J = -40^\circ\text{C}$	1.25	1.55	1.8*				
		$I_C = 20\text{ A}$, $V_{GE} = 4.5\text{ V}$	$T_J = 25^\circ\text{C}$	1.3	1.6	1.9				
			$T_J = 175^\circ\text{C}$	1.2	1.5	1.8				
			$T_J = -40^\circ\text{C}$	1.4	1.75	2.0*				
		Forward Transconductance	gfs	$I_C = 6.0\text{ A}$, $V_{CE} = 5.0\text{ V}$	$T_J = 25^\circ\text{C}$	10		18	25	Mhos

*Maximum Value of Characteristic across Temperature Range.

4. Pulse Test: Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 2\%$.

Dynamic Characteristics

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit
Input Capacitance	C_{ISS}	$V_{CE} = 25\text{ V}$ $f = 10\text{ kHz}$	$T_J = 25^\circ\text{C}$	1100	1300	1500	pF
Output Capacitance	C_{OSS}			70	80	90	
Transfer Capacitance	C_{RSS}			18	20	22	

Switching Characteristics

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit	
Turn-Off Delay Time (Resistive)	$t_{d(off)}$	$V_{CC} = 300\text{ V}$ $I_C = 9.0\text{ A}$ $R_G = 1.0\text{ k}\Omega$ $R_L = 33\ \Omega$ $V_{GE} = 5.0\text{ V}$	$T_J = 25^\circ\text{C}$	6.0	8.0	10	μSec	
			$T_J = 175^\circ\text{C}$	6.0	8.0	10		
Fall Time (Resistive)	t_f		$T_J = 25^\circ\text{C}$	4.0	6.0	8.0		
			$T_J = 175^\circ\text{C}$	8.0	10.5	14		
Turn-Off Delay Time (Inductive)	$t_{d(off)}$		$V_{CC} = 300\text{ V}$ $I_C = 9.0\text{ A}$ $R_G = 1.0\text{ k}\Omega$ $L = 300\ \mu\text{H}$ $V_{GE} = 5.0\text{ V}$	$T_J = 25^\circ\text{C}$	3.0	5.0		7.0
				$T_J = 175^\circ\text{C}$	5.0	7.0		9.0
Fall Time (Inductive)	t_f	$T_J = 25^\circ\text{C}$		1.5	3.0	4.5		
		$T_J = 175^\circ\text{C}$		5.0	7.0	10		
Turn-On Delay Time	$t_{d(on)}$	$V_{CC} = 14\text{ V}$ $I_C = 9.0\text{ A}$ $R_G = 1.0\text{ k}\Omega$ $R_L = 1.5\ \Omega$ $V_{GE} = 5.0\text{ V}$		$T_J = 25^\circ\text{C}$	1.0	1.5	2.0	
				$T_J = 175^\circ\text{C}$	1.0	1.5	2.0	
Rise Time	t_r		$T_J = 25^\circ\text{C}$	4.0	6.0	8.0		
			$T_J = 175^\circ\text{C}$	3.0	5.0	7.0		

Typical Electrical Characteristics

Figure 1. Self Clamped Inductive Switching

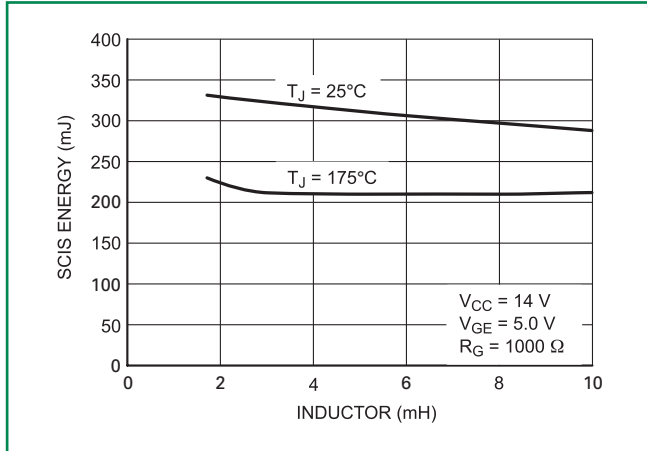


Figure 2. Open Secondary Avalanche Current vs. Temperature

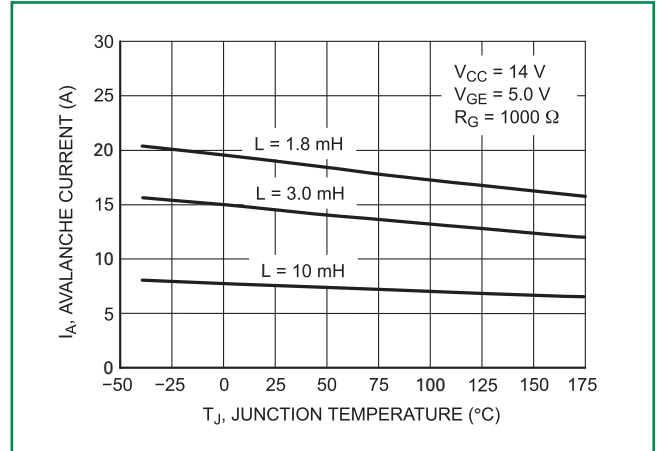


Figure 3. Collector-to-Emitter Voltage vs. Junction Temperature

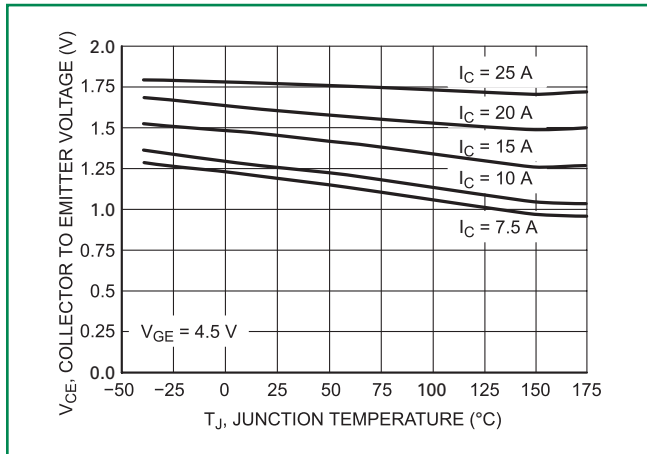


Figure 4. Collector Current vs. Collector-to-Emitter Voltage

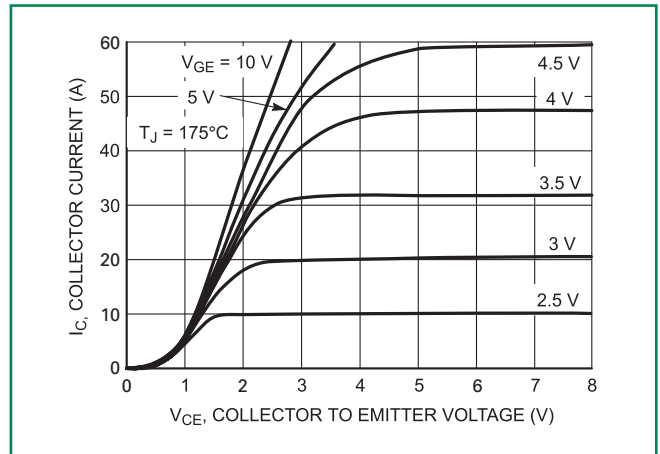


Figure 5. Collector Current vs. Collector-to-Emitter Voltage

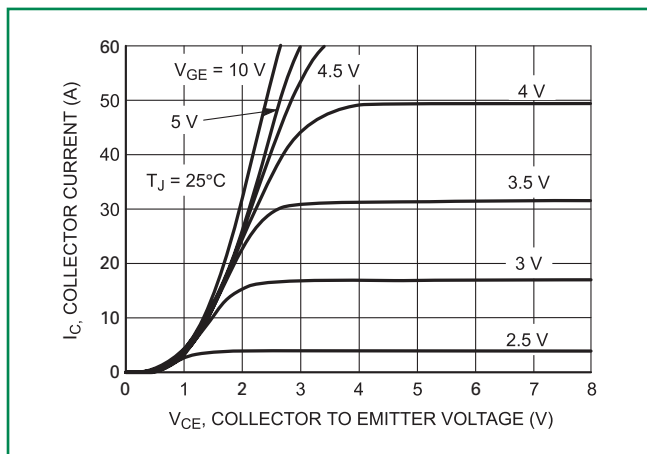


Figure 6. Collector Current vs. Collector-to-Emitter Voltage

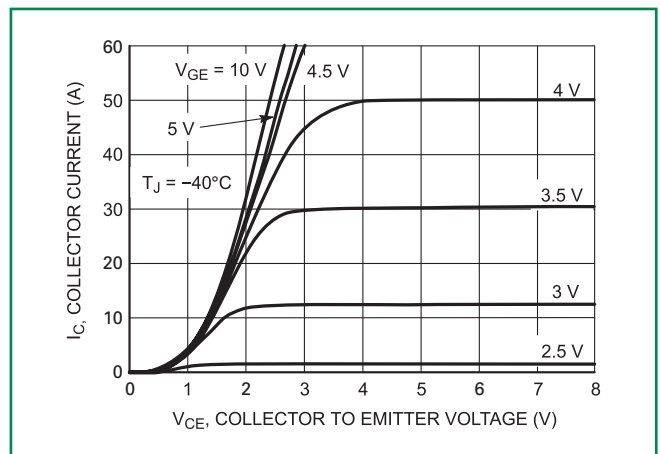


Figure 7. Transfer Characteristics

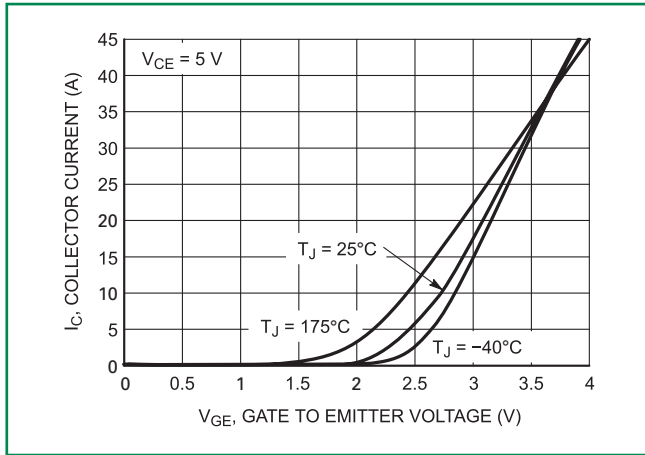


Figure 8. Collector-to-Emitter Leakage Current vs. Temperature

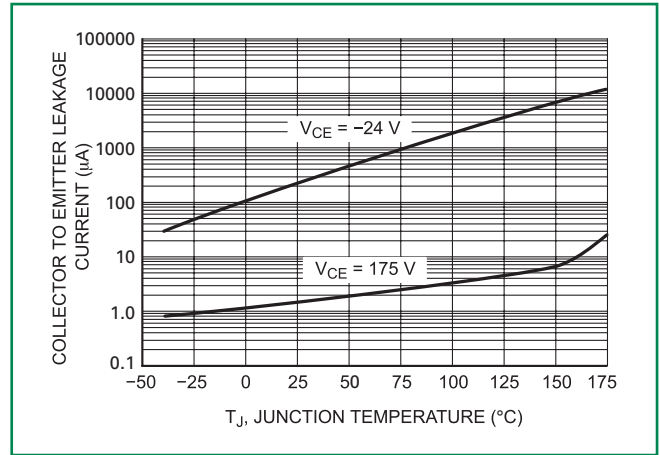


Figure 9. Gate Threshold Voltage vs. Temperature

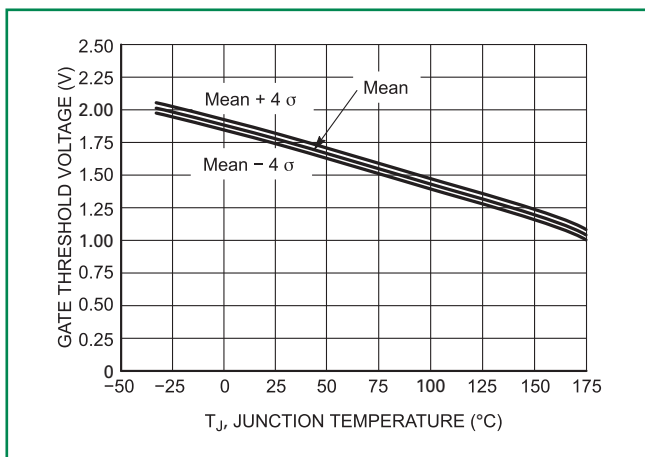


Figure 10. Capacitance vs. Collector-to-Emitter Voltage

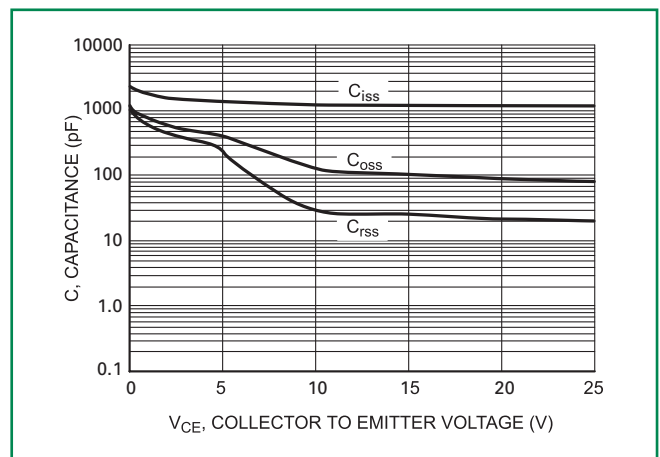


Figure 11. Typical Open Secondary Latch Current vs Temperature

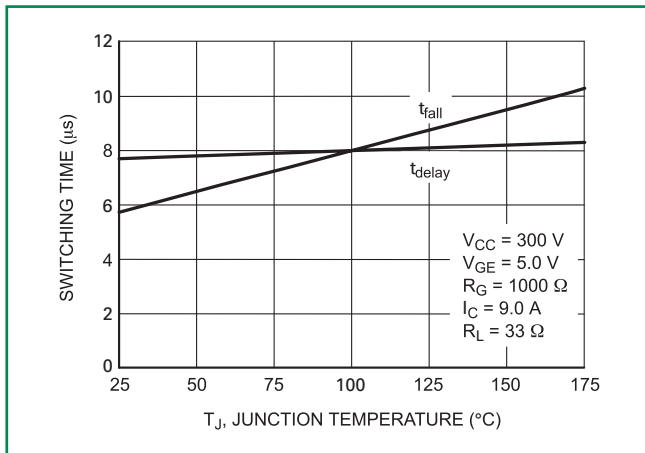


Figure 12. Inductive Switching Fall Time vs. Temperature

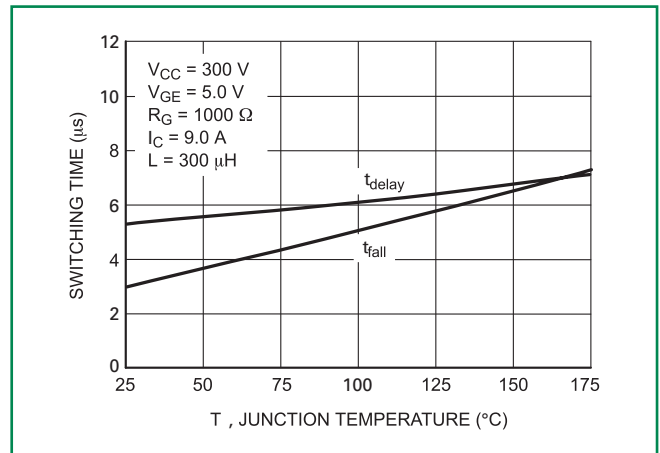


Figure 13. Minimum Pad Transient Thermal Resistance (Non-normalized Junction-to-Ambient)

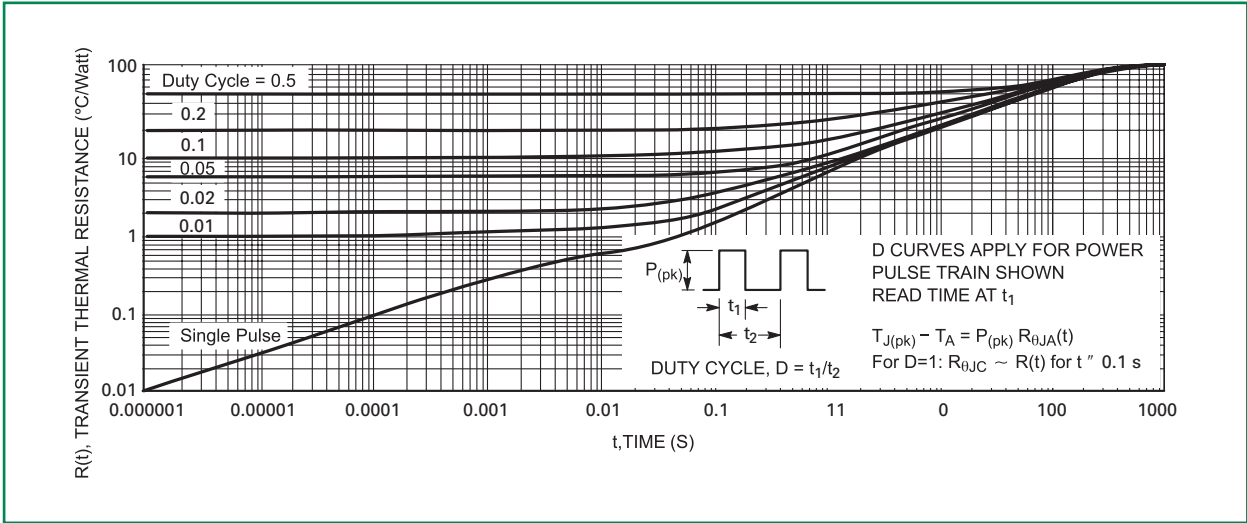


Figure 14. Best Case Transient Thermal Resistance (Non-normalized Junction-to-Case Mounted on Cold Plate)

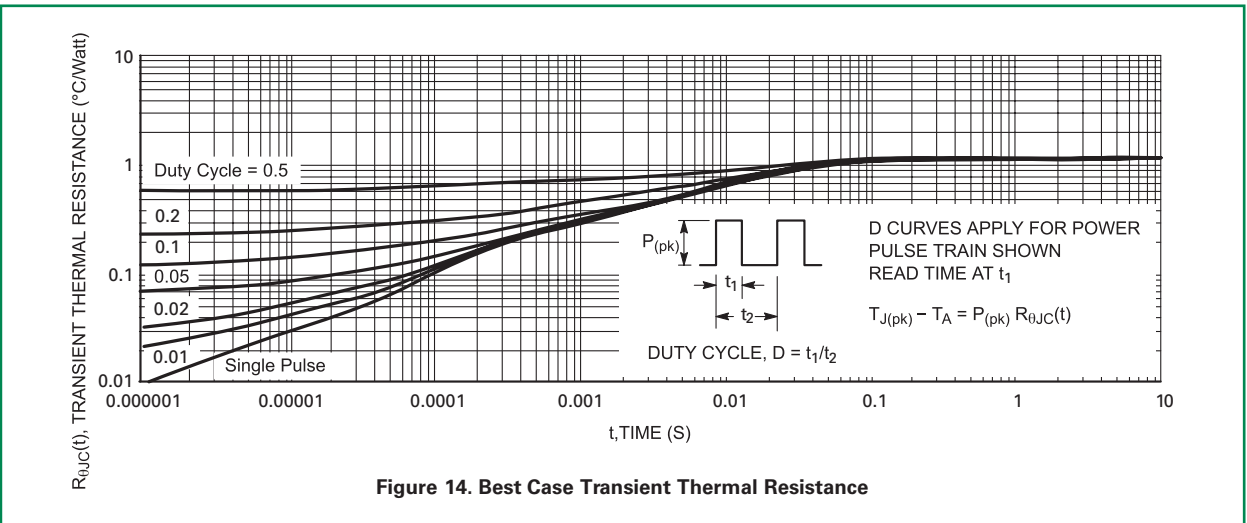


Figure 14. Best Case Transient Thermal Resistance

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